

SURFACE MOUNT SUPER FAST RECOVERY DIODES

VOLTAGE RANGE: 50 - 600V CURRENT: 3.0 A

Features

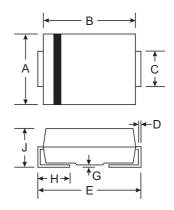
- Glass Passivated Die Construction
- Ideally Suited for Automatic Assembly
- Low Forward Voltage Drop, High Efficiency
- Low Power Loss
- Super-Fast Recovery Time
- Plastic Case Material has UL Flammability Classification Rating 94V-O

Mechanical Data

- Case: SMC/DO-214AB, Molded Plastic
- Terminals: Solder Plated, Solderable per MIL-STD-750, Method 2026
- Polarity: Cathode Band or Cathode Notch
- Marking: Type Number
- Weight: 0.21 grams (approx.)







SMC/DO-214AB							
Dim	Min	Max					
Α	5.59	6.22					
В	6.60	7.11					
С	2.75	3.18					
D	0.15	0.31					
E	7.75	8.13					
G	0.10	0.20					
Н	0.76	1.52					
J	2.00	2.62					
All Dimensions in mm							

Maximum Ratings and Electrical Characteristics T_A = 25°C unless otherwise specified

Single phase, half wave, 60Hz, resistive or inductive load. For capacitive load, derate current by 20%.

Characteristic		Symbol	ER3A	ER3B	ER3C	ER3D	ER3E	ER3G	ER3J	Unit
Peak Repetitive Reverse Voltage Working Peak Reverse Voltage DC Blocking Voltage		VRRM VRWM VR	50	100	150	200	300	400	600	V
RMS Reverse Voltage		VR(RMS)	35	70	105	140	210	280	420	V
Average Rectified Output Current	@T _L = 75°C	lo	3.0							Α
Non-Repetitive Peak Forward Surg 8.3ms Single half sine-wave supering rated load (JEDEC Method)		IFSM	100						А	
Forward Voltage	@I _F = 3.0A	VFM	0.95 1.25 1.7					1.7	V	
Peak Reverse Current At Rated DC Blocking Voltage	@T _A = 25°C @T _A = 100°C	lгм	5.0 500							μΑ
Reverse Recovery Time (Note 1)		trr	35							nS
Typical Junction Capacitance (Note 2)		Cj	45							pF
Typical Thermal Resistance (Note 3)		$R_{ heta}JL$	16							°C/W
Operating and Storage Temperature Range		Tj, TSTG	-65 to +150							°C

- Note: 1. Measured with $I_F = 0.5A$, $I_R = 1.0A$, $I_{rr} = 0.25A$. See figure 5.
 - 2. Measured at 1.0 MHz and applied reverse voltage of 4.0 V DC.
 - 3. Mounted on P.C. Board with 8.0mm² land area.



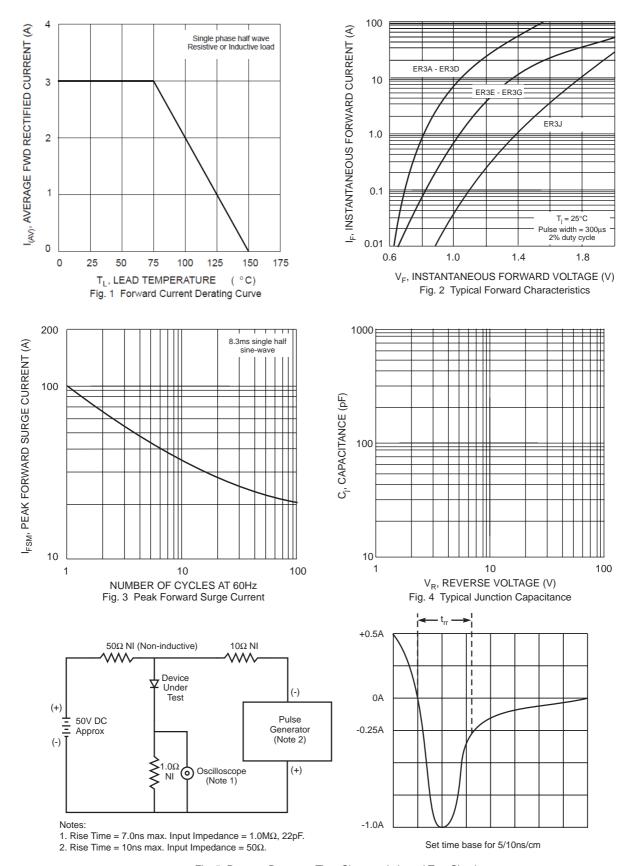


Fig. 5 Reverse Recovery Time Characteristic and Test Circuit